Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination		
1	10/691,212	DORNBUSCH ET AL.	DORNBUSCH ET AL.	
	Examiner	Art Unit		
	Chris C. Chu	2815		

SEARCHED						
	SEARCHED					
Class	Subclass	Date	Examiner			
257	E23.079, E23.052, 786 & 778	9/14/2006	C.C.			
257	686	9/14/2006	C.C.			
	!					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/14/2006	C.C.	
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